Freescale Semiconductor

Technical Data

RF Power Field Effect Transistors

N-Channel Enhancement-Mode Lateral MOSFETs

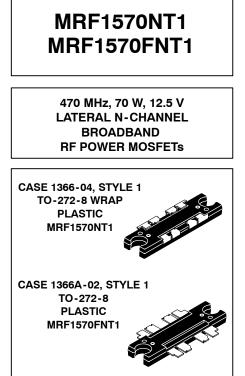
Designed for broadband commercial and industrial applications with frequencies up to 470 MHz. The high gain and broadband performance of these devices make them ideal for large-signal, common source amplifier applications in 12.5 volt mobile FM equipment.

 Specified Performance @ 470 MHz, 12.5 Volts Output Power — 70 Watts Power Gain — 10 dB Efficiency — 50%

• Capable of Handling 20:1 VSWR, @ 15.6 Vdc, 470 MHz, 2 dB Overdrive

Features

- Excellent Thermal Stability
- Characterized with Series Equivalent Large-Signal Impedance Parameters
- Broadband Full Power Across the Band: 135-175 MHz
 400-470 MHz
- Broadband Demonstration Amplifier Information Available Upon Request
- 200°C Capable Plastic Package
- N Suffix Indicates Lead-Free Terminations. RoHS Compliant.
- Available in Tape and Reel. T1 Suffix = 500 Units per 44 mm, 13 inch Reel.



Document Number: MRF1570N

Rev. 8, 9/2006

Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	+0.5, +40	Vdc
Gate-Source Voltage	V _{GS}	± 20	Vdc
Total Device Dissipation @ T _C = 25°C Derate above 25°C	P _D	165 0.5	W W/°C
Storage Temperature Range	T _{stg}	- 65 to +150	°C
Operating Junction Temperature	TJ	200	°C

Table 2. Thermal Characteristics

Characteristic	Symbol	Value ⁽¹⁾	Unit
Thermal Resistance, Junction to Case	$R_{ extsf{ heta}JC}$	0.29	°C/W

Table 3. ESD Protection Characteristics

Test Conditions	Class
Human Body Model	1 (Minimum)
Machine Model	M2 (Minimum)
Charge Device Model	C2 (Minimum)

Table 4. Moisture Sensitivity Level

Test Methodology	Rating	Package Peak Temperature	Unit
Per JESD 22-A113, IPC/JEDEC J-STD-020	1	260	°C

 MTTF calculator available at <u>http://www.freescale.com/rf</u>. Select Tools/Software/Application Software/Calculators to access the MTTF calculators by product.



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Characteristic	Symbol	Min	Тур	Max	Unit
Off Characteristics					
Zero Gate Voltage Drain Current (V _{DS} = 60 Vdc, V _{GS} = 0 Vdc)	I _{DSS}	_	_	1	μA
On Characteristics	·	•			
Gate Threshold Voltage (V _{DS} = 12.5 Vdc, I _D = 0.8 mAdc)	V _{GS(th)}	1	_	3	Vdc
Drain - Source On - Voltage (V _{GS} = 10 Vdc, I _D = 2.0 Adc)		—		1	Vdc
Dynamic Characteristics	·				
Input Capacitance (Includes Input Matching Capacitance) $(V_{DS} = 12.5 \text{ Vdc}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz})$	C _{iss}	-	_	500	pF
Output Capacitance (V _{DS} = 12.5 Vdc, V _{GS} = 0 V, f = 1 MHz)	C _{oss}	_	_	250	pF
Reverse Transfer Capacitance $(V_{DS} = 12.5 \text{ Vdc}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz})$	C _{rss}	_	_	35	pF
RF Characteristics (In Freescale Test Fixture)	·				
	G _{ps}	-	11.5	-	dB
Drain Efficiency (V _{DD} = 12.5 Vdc, P _{out} = 70 W, I _{DQ} = 800 mA) f = 470 MHz	η	_	60	—	%

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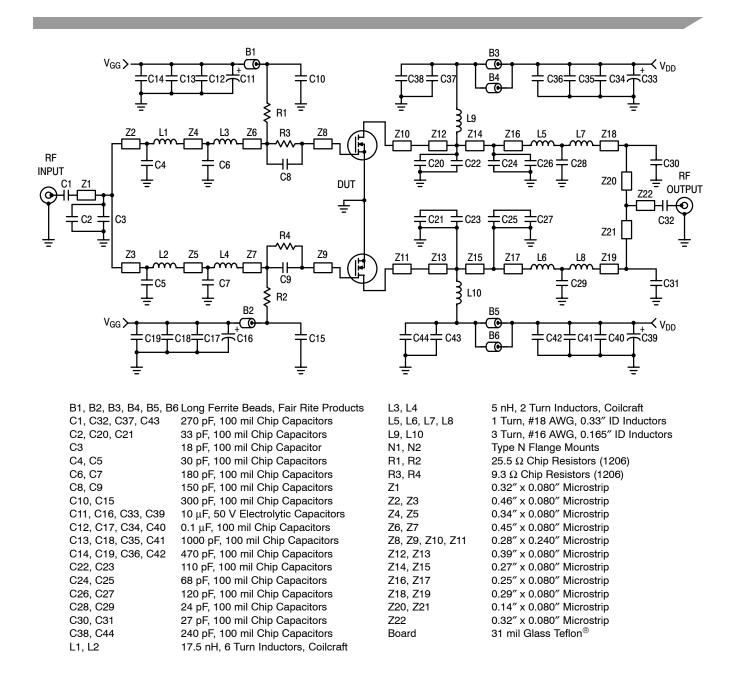
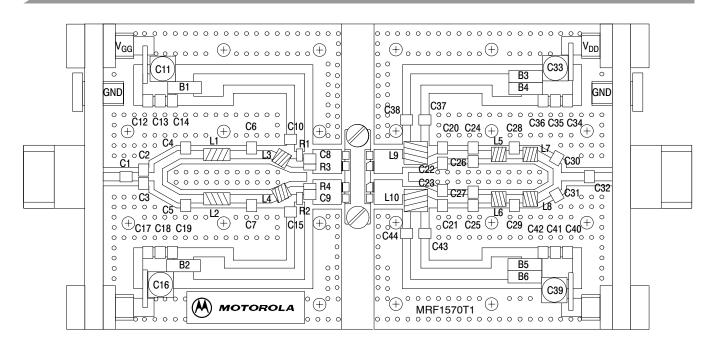


Figure 1. 135 - 175 MHz Broadband Test Circuit Schematic



Freescale has begun the transition of marking Printed Circuit Boards (PCBs) with the Freescale Semiconductor signature/logo. PCBs may have either Motorola or Freescale markings during the transition period. These changes will have no impact on form, fit or function of the current product.



TYPICAL CHARACTERISTICS, 135 - 175 MHz

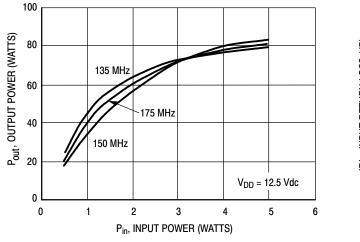


Figure 3. Output Power versus Input Power

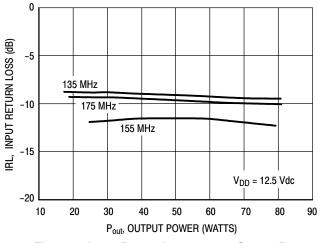
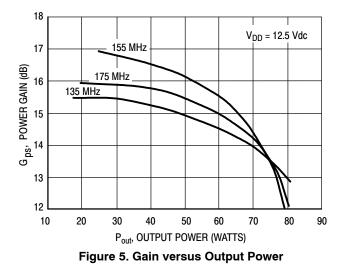


Figure 4. Input Return Loss versus Output Power





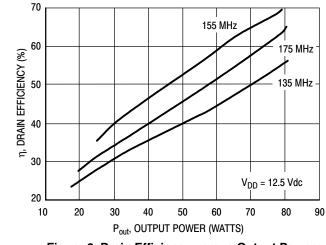


Figure 6. Drain Efficiency versus Output Power

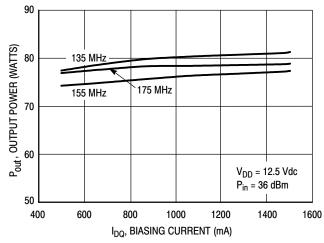


Figure 7. Output Power versus Biasing Current

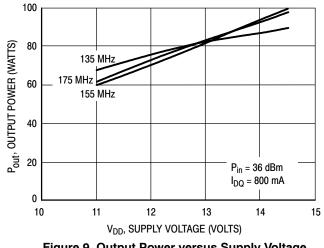


Figure 9. Output Power versus Supply Voltage

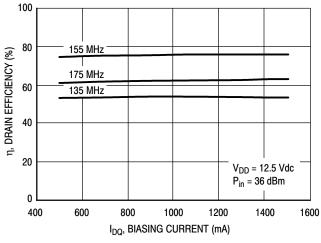


Figure 8. Drain Efficiency versus Biasing Current

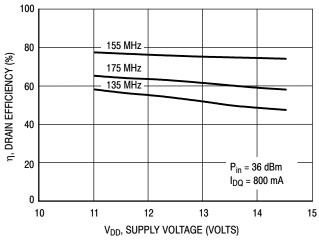


Figure 10. Drain Efficiency versus Supply Voltage

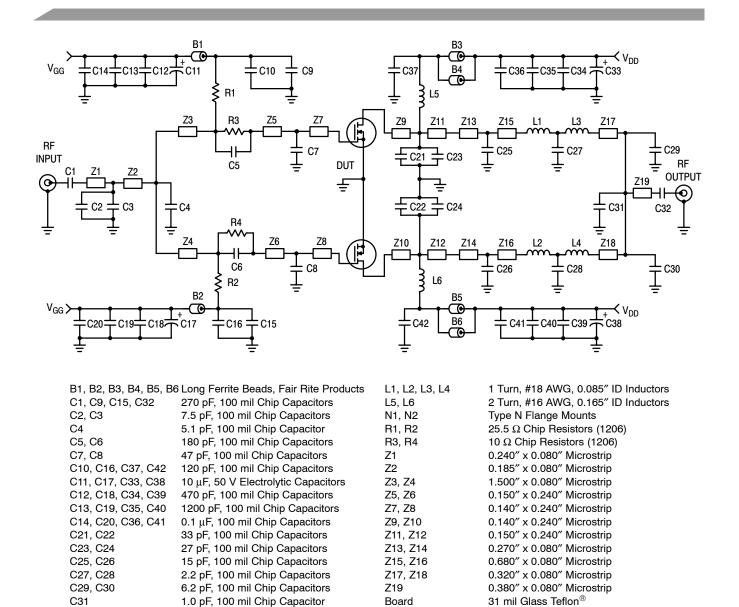
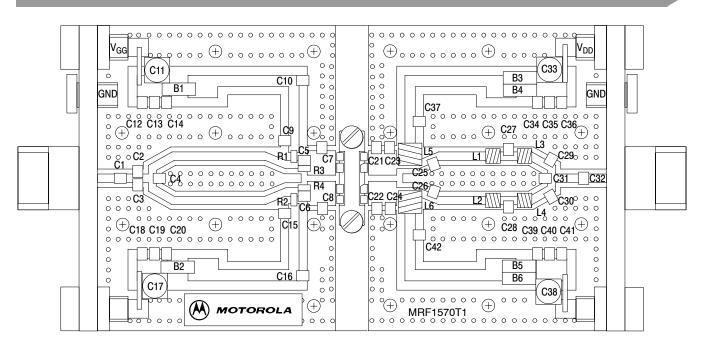
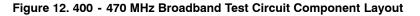
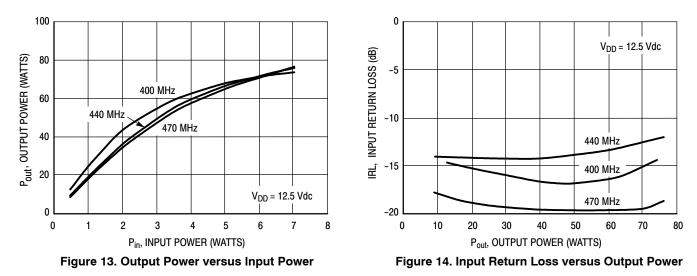


Figure 11. 400 - 470 MHz Broadband Test Circuit Schematic



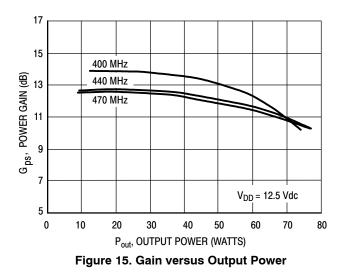
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TYPICAL CHARACTERISTICS, 400 - 470 MHz

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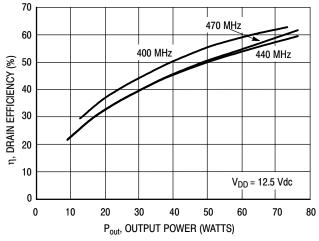
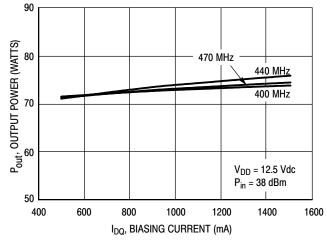


Figure 16. Drain Efficiency versus Output Power





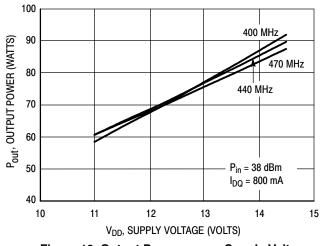


Figure 19. Output Power versus Supply Voltage

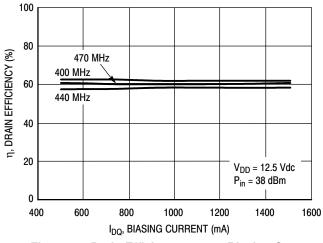


Figure 18. Drain Efficiency versus Biasing Current

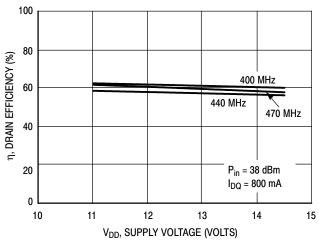
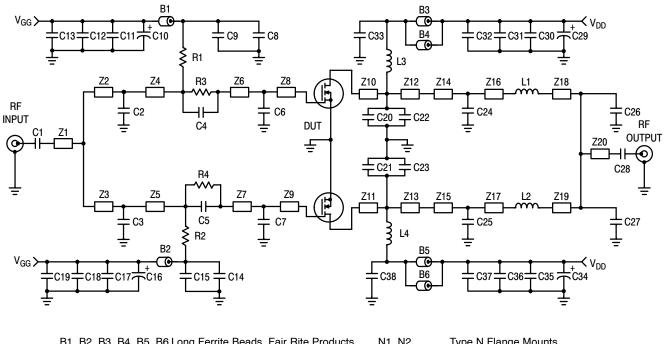
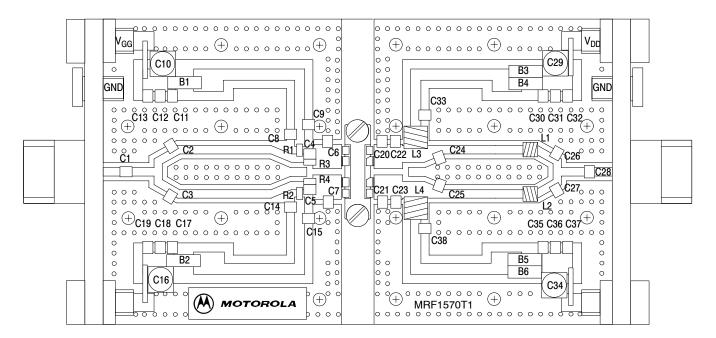


Figure 20. Drain Efficiency versus Supply Voltage



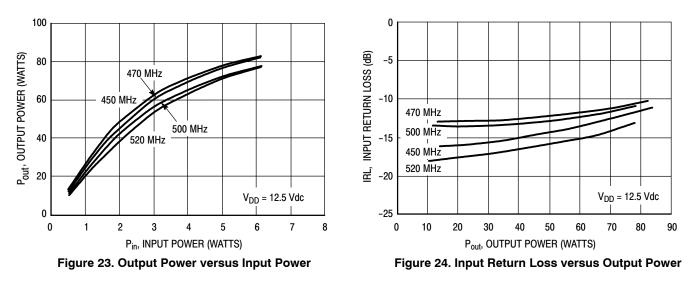
B1, B2, B3, B4, B5, B	6 Long Ferrite Beads, Fair Rite Products	N1, N2	Type N Flange Mounts
C1, C8, C14, C28	270 pF, 100 mil Chip Capacitors	R1, R2	1.0 k Ω Chip Resistors (1206)
C2, C3	10 pF, 100 mil Chip Capacitors	R3, R4	10 Ω Chip Resistors (1206)
C4, C5	180 pF, 100 mil Chip Capacitors	Z1	0.40" x 0.080" Microstrip
C6, C7	47 pF, 100 mil Chip Capacitors	Z2, Z3	0.26" x 0.080" Microstrip
C9, C15, C33, C38	120 pF, 100 mil Chip Capacitors	Z4, Z5	1.35" x 0.080" Microstrip
C10, C16, C29, C34	10 μF, 50 V Electrolytic Capacitors	Z6, Z7	0.17" x 0.240" Microstrip
C11, C17, C30, C35	470 pF, 100 mil Chip Capacitors	Z8, Z9	0.12" x 0.240" Microstrip
C12, C18, C31, C36	1200 pF, 100 mil Chip Capacitors	Z10, Z11	0.14" x 0.240" Microstrip
C13, C19, C32, C37	0.1 μF, 100 mil Chip Capacitors	Z12, Z13	0.15" x 0.240" Microstrip
C20, C21	22 pF, 100 mil Chip Capacitors	Z14, Z15	0.18" x 0.172" Microstrip
C22, C23	20 pF, 100 mil Chip Capacitors	Z16, Z17	1.23" x 0.080" Microstrip
C24, C25, C26, C27	5.1 pF, 100 mil Chip Capacitors	Z18, Z19	0.12" x 0.080" Microstrip
L1, L2	1 Turn, #18 AWG, 0.115" ID Inductors	Z20	0.40" x 0.080" Microstrip
L3, L4	2 Turn, #16 AWG, 0.165" ID Inductors	Board	31 mil Glass Teflon [®]

Figure 21. 450 - 520 MHz Broadband Test Circuit Schematic



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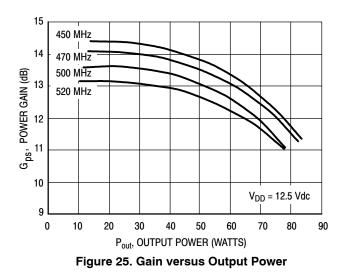


TYPICAL CHARACTERISTICS, 450 - 520 MHz

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TYPICAL CHARACTERISTICS, 450 - 520 MHz



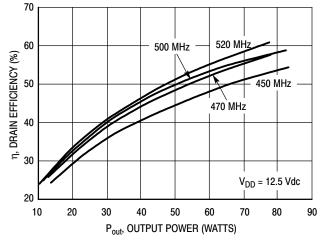


Figure 26. Drain Efficiency versus Output Power

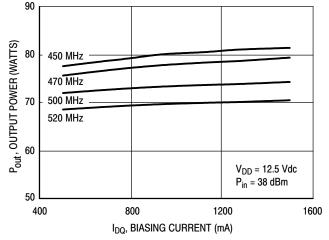
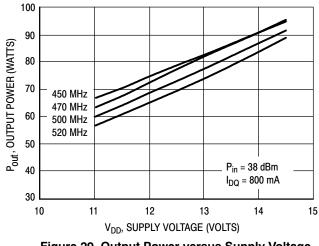
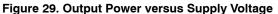
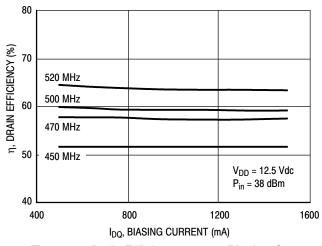


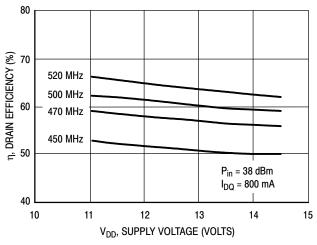
Figure 27. Output Power versus Biasing Current

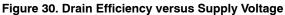




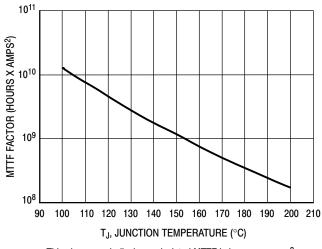






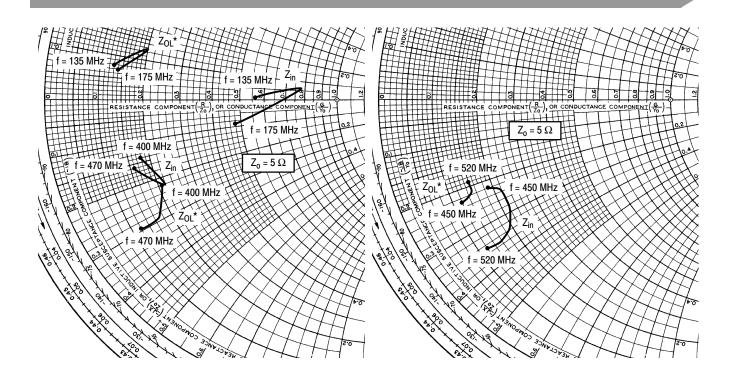


TYPICAL CHARACTERISTICS



This above graph displays calculated MTTF in hours x ampere² drain current. Life tests at elevated temperatures have correlated to better than $\pm 10\%$ of the theoretical prediction for metal failure. Divide MTTF factor by $I_D{}^2$ for MTTF in a particular application.





V_{DD} = 12.5 V, I_{DQ} = 0.8 A, P_{out} = 70 W

f MHz	Z _{in} Ω	Ζ_{ΟL}* Ω
135	2.8 +j0.05	0.65 +j0.42
155	3.9 +j0.34	1.01 +j0.63
175	2.4 -j0.47	0.71 +j0.37

 V_{DD} = 12.5 V, I_{DQ} = 0.8 A, P_{out} = 70 W

f MHz	Z_{in} Ω	Ζ_{ΟL}* Ω
400	0.92 -j0.71	1.05 -j1.10
440	1.12 -j1.11	0.83 -j1.45
470	0.82 -j0.79	0.59 -j1.43

V_{DD} = 12.5 V, I_{DQ} = 0.8 A, P_{out} = 70 W

f MHz	Z_{in} Ω	Ζ_{ΟL}* Ω
450	0.94 -j1.12	0.61 -j1.14
470	1.03 -j1.17	0.62 -j1.12
500	0.95 -j1.71	0.75 -j1.03
520	0.62 -j1.74	0.77 -j0.97

- Z_{in} = Complex conjugate of source impedance.
- $$\begin{split} Z_{OL}{}^{\star} &= & Complex \ conjugate \ of \ the \ load \\ impedance \ at \ given \ output \ power, \\ voltage, \ frequency, \ and \ \eta_D > 50 \ \%. \end{split}$$
- Notes: Impedance Z_{in} was measured with input terminated at 50 $\Omega.$ Impedance Z_{OL} was measured with output terminated at 50 $\Omega.$

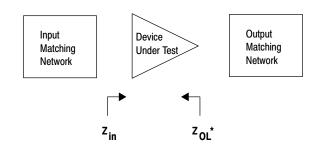


Figure 32. Series Equivalent Input and Output Impedance

DESIGN CONSIDERATIONS

This device is a common-source, RF power, N-Channel enhancement mode, Lateral <u>Metal-Oxide Semiconductor</u> <u>Field-Effect Transistor (MOSFET)</u>. Freescale Application Note AN211A, "FETs in Theory and Practice", is suggested reading for those not familiar with the construction and characteristics of FETs.

This surface mount packaged device was designed primarily for VHF and UHF mobile power amplifier applications. Manufacturability is improved by utilizing the tape and reel capability for fully automated pick and placement of parts. However, care should be taken in the design process to insure proper heat sinking of the device.

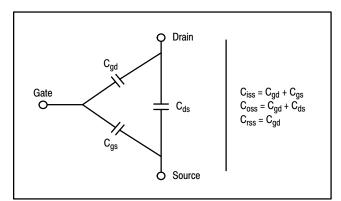
The major advantages of Lateral RF power MOSFETs include high gain, simple bias systems, relative immunity from thermal runaway, and the ability to withstand severely mismatched loads without suffering damage.

MOSFET CAPACITANCES

The physical structure of a MOSFET results in capacitors between all three terminals. The metal oxide gate structure determines the capacitors from gate-to-drain (C_{gd}), and gate-to-source (C_{gs}). The PN junction formed during fabrication of the RF MOSFET results in a junction capacitance from drain-to-source (C_{ds}). These capacitances are characterized as input (C_{iss}), output (C_{oss}) and reverse transfer (C_{rss}) capacitances on data sheets. The relationships between the inter-terminal capacitances and those given on data sheets are shown below. The C_{iss} can be specified in two ways:

- 1. Drain shorted to source and positive voltage at the gate.
- 2. Positive voltage of the drain in respect to source and zero volts at the gate.

In the latter case, the numbers are lower. However, neither method represents the actual operating conditions in RF applications.



DRAIN CHARACTERISTICS

One critical figure of merit for a FET is its static resistance in the full-on condition. This on-resistance, $R_{DS(on)}$, occurs in the linear region of the output characteristic and is specified at a specific gate-source voltage and drain current. The drain-source voltage under these conditions is termed $V_{DS(on)}$. For MOSFETs, $V_{DS(on)}$ has a positive temperature coefficient at high temperatures because it contributes to the power dissipation within the device.

 $\mathsf{BV}_{\mathsf{DSS}}$ values for this device are higher than normally required for typical applications. Measurement of $\mathsf{BV}_{\mathsf{DSS}}$ is not recommended and may result in possible damage to the device.

GATE CHARACTERISTICS

The gate of the RF MOSFET is a polysilicon material, and is electrically isolated from the source by a layer of oxide. The DC input resistance is very high - on the order of $10^9 \Omega$ — resulting in a leakage current of a few nanoamperes.

Gate control is achieved by applying a positive voltage to the gate greater than the gate-to-source threshold voltage, $V_{GS(th)}$.

Gate Voltage Rating — Never exceed the gate voltage rating. Exceeding the rated V_{GS} can result in permanent damage to the oxide layer in the gate region.

Gate Termination — The gates of these devices are essentially capacitors. Circuits that leave the gate open-circuited or floating should be avoided. These conditions can result in turn-on of the devices due to voltage build-up on the input capacitor due to leakage currents or pickup.

Gate Protection — These devices do not have an internal monolithic zener diode from gate-to-source. If gate protection is required, an external zener diode is recommended. Using a resistor to keep the gate-to-source impedance low also helps dampen transients and serves another important function. Voltage transients on the drain can be coupled to the gate through the parasitic gate-drain capacitance. If the gate-to-source impedance and the rate of voltage change on the drain are both high, then the signal coupled to the gate may be large enough to exceed the gate-threshold voltage and turn the device on.

DC BIAS

Since this device is an enhancement mode FET, drain current flows only when the gate is at a higher potential than the source. RF power FETs operate optimally with a quiescent drain current (I_{DQ}), whose value is application dependent. This device was characterized at I_{DQ} = 800 mA, which is the suggested value of bias current for typical applications. For special applications such as linear amplification, I_{DQ} may have to be selected to optimize the critical parameters.

The gate is a dc open circuit and draws no current. Therefore, the gate bias circuit may generally be just a simple resistive divider network. Some special applications may require a more elaborate bias system.

GAIN CONTROL

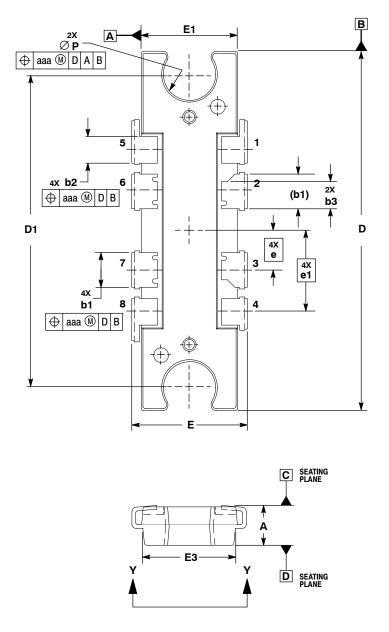
Power output of this device may be controlled to some degree with a low power dc control signal applied to the gate, thus facilitating applications such as manual gain control, ALC/AGC and modulation systems. This characteristic is very dependent on frequency and load line.

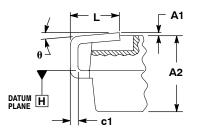
AMPLIFIER DESIGN

Impedance matching networks similar to those used with bipolar transistors are suitable for this device. For examples see Freescale Application Note AN721, "Impedance Matching Networks Applied to RF Power Transistors." Large-signal impedances are provided, and will yield a good first pass approximation.

Since RF power MOSFETs are triode devices, they are not unilateral. This coupled with the very high gain of this device yields a device capable of self oscillation. Stability may be achieved by techniques such as drain loading, input shunt resistive loading, or output to input feedback. The RF test fixture implements a parallel resistor and capacitor in series with the gate, and has a load line selected for a higher efficiency, lower gain, and more stable operating region. See Freescale Application Note AN215A, "RF Small-Signal Design Using Two-Port Parameters" for a discussion of two port network theory and stability.

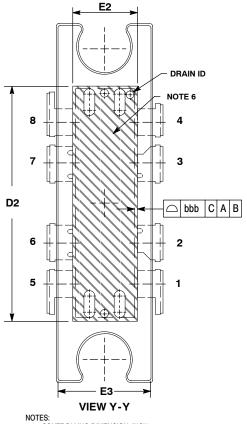
PACKAGE DIMENSIONS





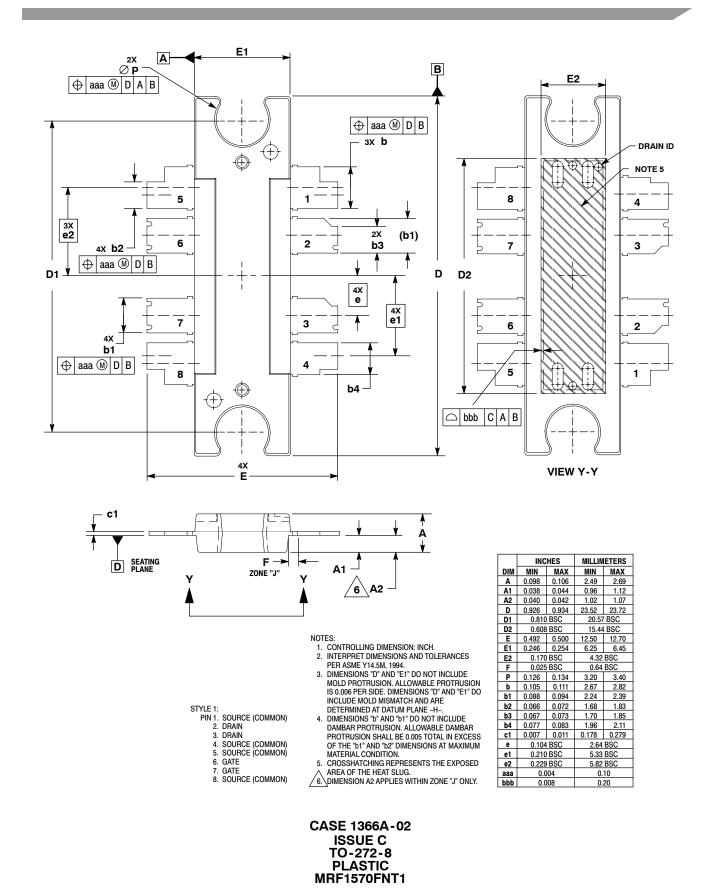


CASE 1366-04 **ISSUE D** TO-272-8 WRAP PLASTIC **MRF1570NT1**



- VIEWYY-Y NOTES: 1. CONTROLLING DIMENSION: INCH. 2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994. 3. DATUM PLANE -H- IS LOCATED AT TOP OF LEAD AND IS CONCIDENT WITH THE LEAD WHERE THE LEAD EXITS THE PLASTIC BODY AT THE TOP OF THE PARTING LINE. DIVENUOLIN LANUE FOR DIVENUES INCL.
- TOP OF THE PARTING LINE. 4. DIMENSION D AND E1 DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS 0.006 PER SIDE. DIMENSION D AND E1 DO INCLUDE MOLD MISMATCH AND ARE DETERMINED ATD DATUM PLANE -H-. 5. DIMENSIONS D1 AND b2 DO NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.005 TOTAL IN EXCESS OF THE b1 AND b2 DIMENSIONS AT MAXIMUM MATERIAL CONDITION. MATERIAL CONDITION. 6. CROSSHATCHING REPRESENTS THE EXPOSED
- AREA OF THE HEAT SLUG.

	INCHES MILLIMETERS		ETERS	
DIM	MIN	MAX	MIN	MAX
Α	0.098	0.108	2.49	2.74
A1	0.000	0.004	0.00	0.10
A2	0.100	0.104	2.54	2.64
D	0.928	0.932	23.57	23.67
D1	0.810	BSC	20.57	' BSC
D2	0.608	BSC	15.44	BSC
Е	0.296	0.304	7.52	7.72
E1	0.248	0.252	6.30	6.40
E2	0.170	BSC	4.32 BSC	
E3	0.241	0.245	6.12	6.22
L	0.060	0.070	1.52	1.78
Ρ	0.126	0.134	3.20	3.40
b1	0.088	0.094	2.24	2.39
b2	0.066	0.072	1.68	1.83
b3	0.067	0.073	1.70	1.85
c1	0.007	0.011	0.178	0.279
е	0.104	BSC	2.64	BSC
e1		BSC	5.33	BSC
θ	0°	6 °	0 °	6 °
aaa	0.0	004	0.	10
bbb	0.0	0.008		20



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